Erratum to

Sub-gap defect density characterization of molybdenum oxide: An annealing study for solar cell applications (Nano Research, (2020), 13, 12, (3416-3424), 10.1007/s12274-020-3029-9)

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Erratum to: Sub-gap defect density characterization of molybdenum oxide: An annealing study for solar cell applications

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Erratum to

Nano Research 2020, 13(12): 3416–3424
https://doi.org/10.1007/s12274-020-3029-9

Ref. [56] was unfortunately wrong,

Instead of

[56] Corless, R. M.; Gonnet, G. H.; Hare, D. E. G.; Jeffrey, D. J.; Knuth, D. E. On the Lambert *W* function. *Adv. Comput. Math.* **1996**, *5*, 329–359.

It should be changed to

Biswas, R. K.; Khan, P.; Mukherjee, S.; Mukhopadhyay, A. K.; Ghosh, J.; Muraleedharan, K. Study of short range structure of amorphous Silica from PDF using Ag radiation in laboratory XRD system, RAMAN and NEXAFS. *J. Non. Cryst. Solids* **2018**, *488*, 1–9.

Some entries in Table 2 were unfortunately misprinted.

Instead of

Table 2 DOS parameters extracted from the deconvolution of the absorption coefficient for the 20-nm thick MoOx films annealed at different temperatures and in different annealing ambiances

Temp. (°C)	Atm.	E_{0V} (meV)	E_{0C} (meV)	A_D ($eV^{-1}\cdot cm^{-3}$)	E_D (eV)	W (meV)	A_P ($eV^{-1}\cdot cm^{-3}$)	E_P (eV)	E_{op} (meV)
As-deposited		109	84	1.5 E15	1.10	30	2.9 E3	1.57	27
100	Air	89	59	2.73 E15	1.10	20	1.14 E5	1.58	25
130	Air	93	55	4.46 E15	1.10	20	2.19 E5	1.57	28
150	Air	84	43	8.25 E15	1.10	20	3.91 E5	1.58	28
200	Air	88	56	1.18 E16	1.10	20	4.44 E5	1.55	30
250	Air	99	59	1.15 E16	1.10	20	4.88 E5	1.53	27
100	H_2	91	49	5.18 E15	1.11	20	2.49 E5	1.57	29
130	H_2	84	35	7.21 E15	1.09	20	3.49 E5	1.57	29
150	H_2	86	42	1.02 E16	1.09	30	5.31 E5	1.58	32
200	H_2	93	64	1.42 E16	1.11	30	7.26 E5	1.57	34
250	H_2	104	65	1.98 E16	1.14	30	1.03 E6	1.56	42
100	Ar	87	51	4.14 E15	1.11	20	1.98 E5	1.57	29
130	Ar	85	52	4.71 E15	1.09	20	2.23 E5	1.58	28
150	Ar	63	59	5.57 E15	1.11	20	3.60 E5	1.61	29
200	Ar	85	38	1.13 E16	1.10	30	5.96 E5	1.57	32
250	Ar	103	65	1.76 E16	1.12	30	8.51 E5	1.56	37

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It should be changed to

Table 2 DOS parameters extracted from the deconvolution of the absorption coefficient for the 20-nm thick MoO_x films annealed at different temperatures and in different annealing ambiances

Temp. (°C)	Atm.	E_{0V} (meV)	E_{0C} (meV)	A_D ($eV^{-1}·cm^{-3}$)	E_D (eV)	W (meV)	A_P ($eV^{-1}·cm^{-3}$)	E_P (eV)	E_{op} (meV)
As-deposited		109	84	9.21E+14	1.10	30	4.32E+03	0.800	50.0
100	Air	89	59	2.69E+15	1.10	20	1.13E+04	0.795	50.3
130	Air	93	55	3.86E+15	1.10	20	2.18E+04	0.810	54.4
150	Air	84	43	6.79E+15	1.10	20	3.95E+04	0.810	62.5
200	Air	88	56	1.15E+16	1.10	20	5.06E+04	0.795	52.9
250	Air	99	59	1.05E+16	1.10	20	4.89E+04	0.785	51.0
100	H_2	91	49	4.32E+15	1.11	20	2.46E+04	0.805	57.4
130	H_2	84	35	5.75E+15	1.09	20	3.52E+04	0.810	59.8
150	H_2	86	42	8.93E+15	1.09	30	4.91E+04	0.810	59.8
200	H_2	93	64	1.37E+16	1.11	30	6.12E+04	0.800	55.1
250	H_2	104	65	1.86E+16	1.14	30	7.53E+04	0.805	54.8
100	Ar	87	51	3.71E+15	1.11	20	1.93E+04	0.795	58.1
130	Ar	85	52	3.93E+15	1.09	20	2.25E+04	0.810	57.1
150	Ar	63	59	4.29E+15	1.11	20	3.44E+04	0.825	61.4
200	Ar	85	38	1.09E+16	1.10	30	5.24E+04	0.800	50.0
250	Ar	103	65	1.72E+16	1.12	30	7.01E+04	0.795	66.5

In page 3420 of the original paper, the two data in the last sentence of Section 3.3 were unfortunately misprinted.

Instead of

Finally, E_P and E_{op} resulted unchanged by the annealing conditions, with mean values of 1.57 eV and 30 meV, respectively.

It should be changed to

Finally, E_P and E_{op} resulted unchanged by the annealing conditions, with mean values of 0.80 eV and 55 meV, respectively.

In page 3421 of the original paper, the two data in the first paragraph of Section 4 were unfortunately misprinted.

Instead of

The polaron binding energy resulted in approximately 1.57 eV while the longitudinal-optical phonon energy in 30 meV.

It should be changed to

The polaron binding energy resulted in approximately 0.80 eV while the longitudinal-optical phonon energy in 55 meV.

The online version of the original article can be found at
https://doi.org/10.1007/s12274-020-3029-9